



深圳市矽源特科技有限公司

ShenZhen ChipSourceTek Technology Co. ,Ltd.



MSH3509 V1.0

## P-Channel Enhancement Mode Field Effect Transistor

General Features		
V <sub>DSS</sub>	I <sub>D</sub>	R <sub>D(S(ON))</sub> (mΩ) Typ
-30V	-55A	10 @ V <sub>G</sub> S=-10.0V
		15 @ V <sub>G</sub> S=-4.5V

### DESCRIPTION

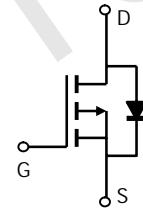
The MSH3509 uses advanced trench technology and design to provide excellent R<sub>D(S(ON))</sub> with low gate charge. It can be used in a wide variety of applications.

- High density cell design for ultra low Rdson
- Fully characterized avalanche voltage and current
- Good stability and uniformity with high E<sub>AS</sub>
- Excellent package for good heat dissipation
- Special process technology for high ESD capability

### APPLICATIONS

- Power Management in Note book
- Portable Equipment
- Battery Powered System
- Load Switch

MSH3509  
YYWW XX



P-DFN3X3 top and bottom view

Marking and pin Assignment

Schematic diagram

### Absolute Maximum Ratings T<sub>A</sub>=25°C unless otherwise noted

Parameter	Symbol	Maximum		Units
Drain-Source Voltage	V <sub>DS</sub>	-30		V
Gate-Source Voltage	V <sub>GS</sub>	±20		V
Continuous Drain Current <sup>A</sup>	I <sub>D</sub>	-55		A
T <sub>A</sub> =70°C		-38		
Pulsed Drain Current <sup>B</sup>	I <sub>DM</sub>	-180		
Power Dissipation <sup>A</sup>	P <sub>D</sub>	50		W
T <sub>A</sub> =70°C		35		
Junction and Storage Temperature Range	T <sub>J</sub> , T <sub>STG</sub>	-55 to 150		°C

### Thermal Characteristics

Parameter	Symbol	Typ	Max	Units
Maximum Junction-to-Ambient <sup>A</sup>	R <sub>θJA</sub>	45	62	°C/W
Steady-State		54	75	°C/W
Maximum Junction-to-Lead <sup>C</sup>	R <sub>θJL</sub>	21	30	°C/W

Electrical Characteristics ( $T_J=25^\circ\text{C}$  unless otherwise noted)

Symbol	Parameter	Limit	Min	Typ	Max	Unit
<b>STATIC</b>						
BV <sub>DSS</sub>	Drain-Source Breakdown Voltage	V <sub>GS</sub> =0, I <sub>D</sub> =-250 $\mu\text{A}$	-30			V
V <sub>G(S(th))</sub>	Gate Threshold Voltage	V <sub>DS</sub> =V <sub>GS</sub> , I <sub>D</sub> =-250 $\mu\text{A}$	1		3	V
I <sub>CSS</sub>	Gate Body Leakage	V <sub>DS</sub> =0V, V <sub>GS</sub> =±20V			±100	nA
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	V <sub>DS</sub> =-30V, V <sub>GS</sub> =0V			1	$\mu\text{A}$
R <sub>D(S(ON))</sub>	Drain-Source On-Resistance	V <sub>GS</sub> =-10V, I <sub>D</sub> = -30A		10	12	mΩ
		V <sub>GS</sub> =-4.5V, I <sub>D</sub> =-15A		15	17	
V <sub>SD</sub>	Diode Forward Voltage	I <sub>S</sub> =-2.7A, V <sub>GS</sub> =0V		0.7		V
<b>DYNAMIC</b>						
Q <sub>G</sub>	Total Gate Charge	V <sub>DS</sub> =-15V, V <sub>GS</sub> =-4.5V, I <sub>D</sub> =-15A		33		nC
Q <sub>GS</sub>	Gate-Source Charge	V <sub>DS</sub> =-15V,		11		
Q <sub>GD</sub>	Gate-Drain Charge	V <sub>GS</sub> =-4.5V, I <sub>D</sub> =-15A		13		
C <sub>ISS</sub>	Input capacitance	V <sub>DS</sub> =-15V, V <sub>GS</sub> =0V, f=1MHz		3500		pF
C <sub>OSS</sub>	Output Capacitance			510		
C <sub>RSS</sub>	Reverse Transfer Capacitance			420		
t <sub>d(on)</sub>	Turn-On Delay Time	V <sub>DD</sub> =-15V, R <sub>L</sub> =15Ω I <sub>D</sub> =-15A , V <sub>GEN</sub> =-10V R <sub>G</sub> =3Ω		8		ns
t <sub>r</sub>	Turn-On Rise Time			18		
t <sub>d(off)</sub>	Turn-Off Delay Time			78		
t <sub>f</sub>	Turn-Off Fall Time			42		

A: The value of  $R_{QJA}$  is measured with the device mounted on 1in<sup>2</sup> FR-4 board with 2oz. Copper, in a still air environment with  $T_A=25^\circ\text{C}$ . The value in any given application depends on the user's specific board design. The current rating is based on the  $t \leq 10\text{s}$  thermal resistance rating.

B: Repetitive rating, pulse width limited by junction temperature.

C. The  $R_{QJA}$  is the sum of the thermal impedance from junction to lead  $R_{QJL}$  and lead to ambient.

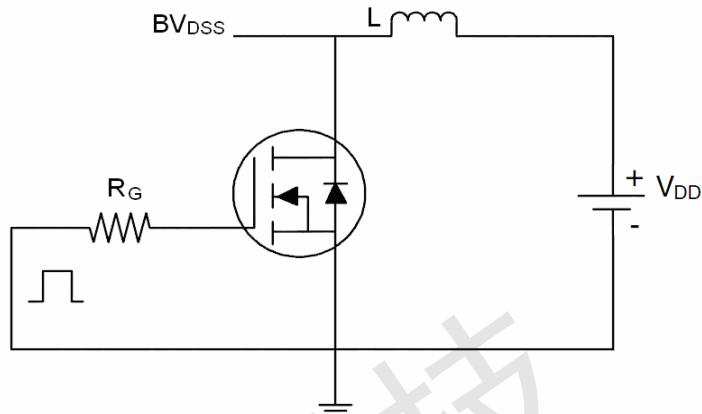
D. The static characteristics in Figures 1 to 6,12,14 are obtained using 80μs pulses, duty cycle 0.5% max.

E. These tests are performed with the device mounted on 1 in<sup>2</sup> FR-4 board with 2oz. Copper, in a still air environment with  $T_A=25^\circ\text{C}$ . The SOA curve provides a single pulse rating.

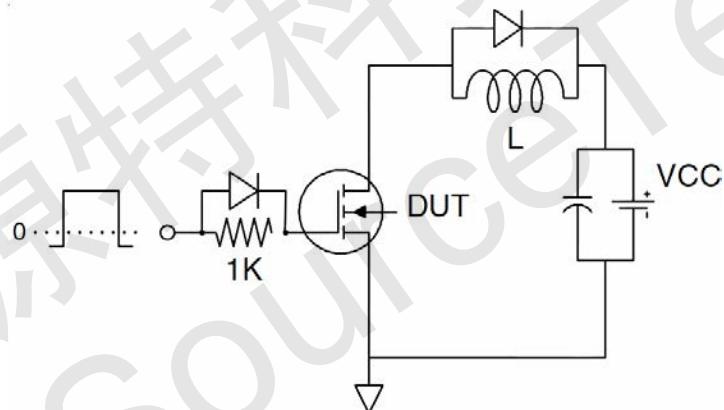


### Test Circuit

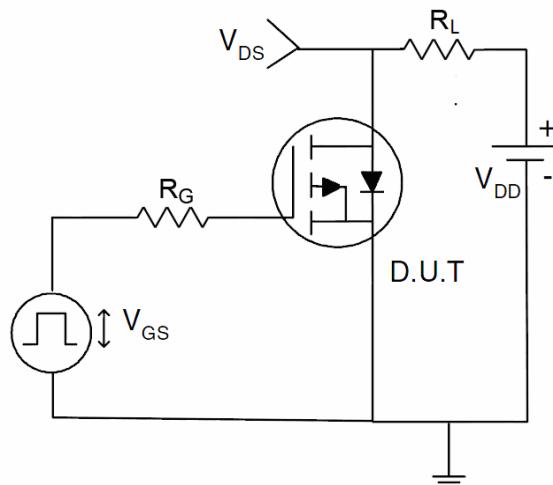
#### 1) E<sub>AS</sub> Test Circuits



#### 2) Gate Charge Test Circuit



#### 3) Switch Time Test Circuit





### Typical Electrical and Thermal Characteristics (Curves)

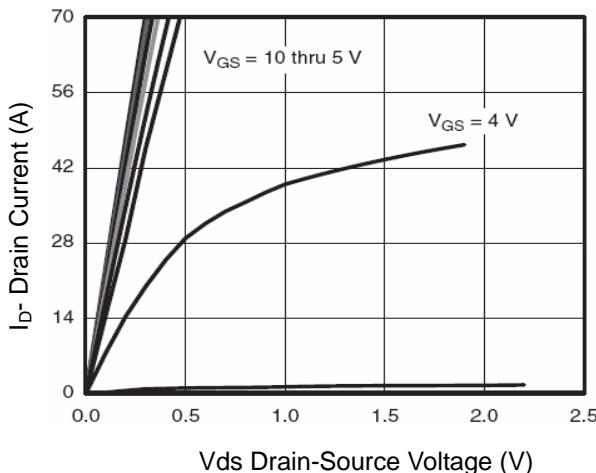


Figure 1 Output Characteristics

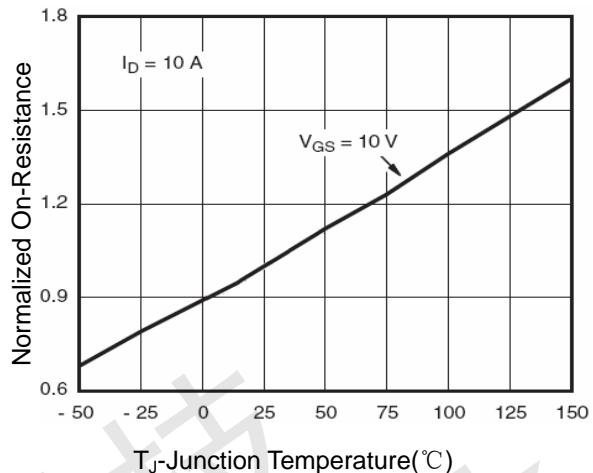


Figure 4 Rdson-Junction Temperature

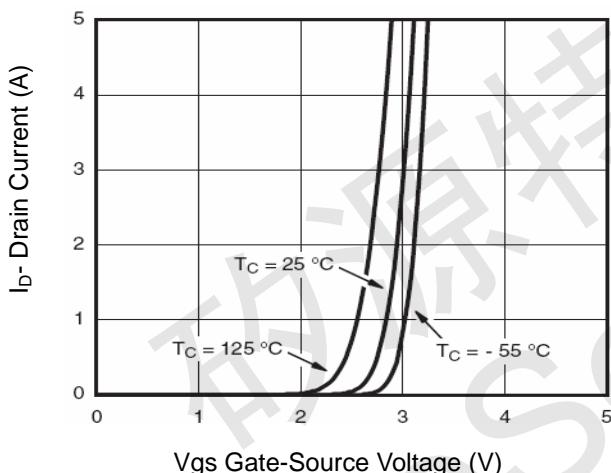


Figure 2 Transfer Characteristics

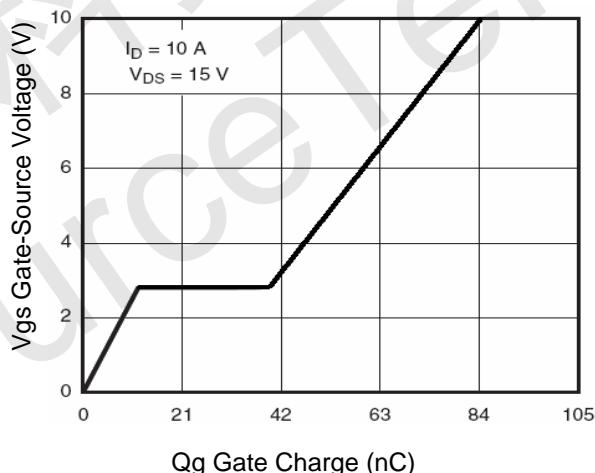


Figure 5 Gate Charge

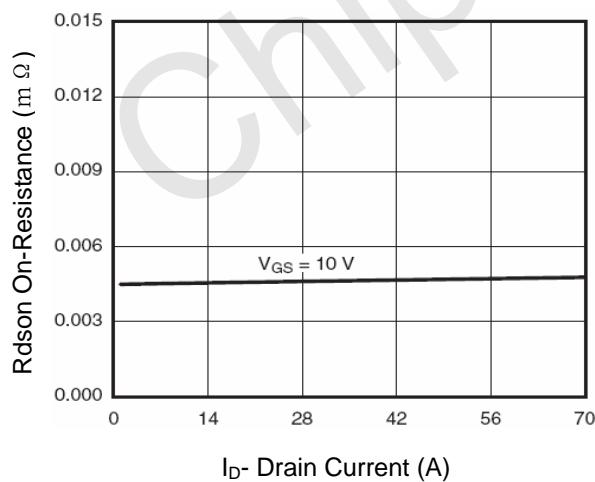


Figure 3 Rdson- Drain Current

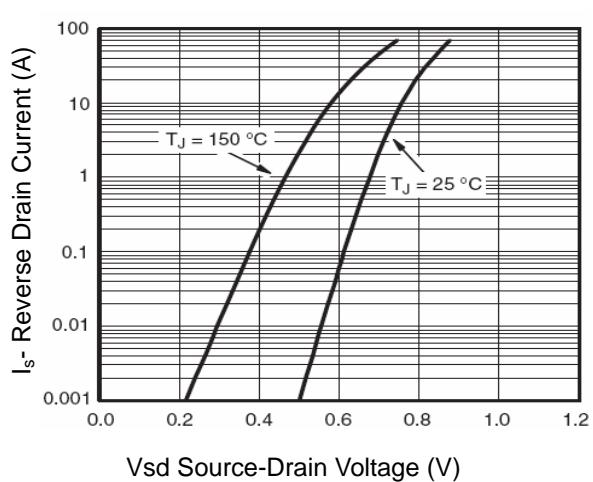


Figure 6 Source- Drain Diode Forward

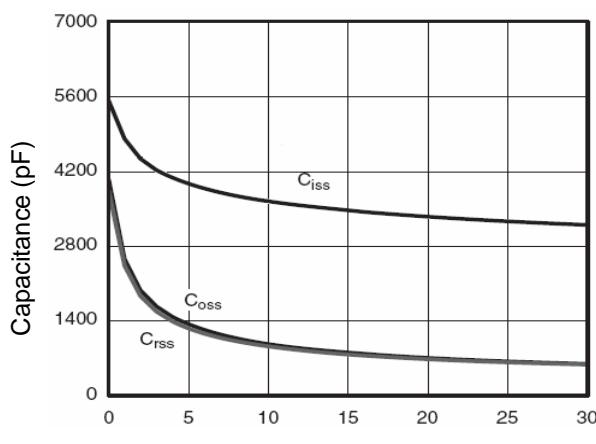


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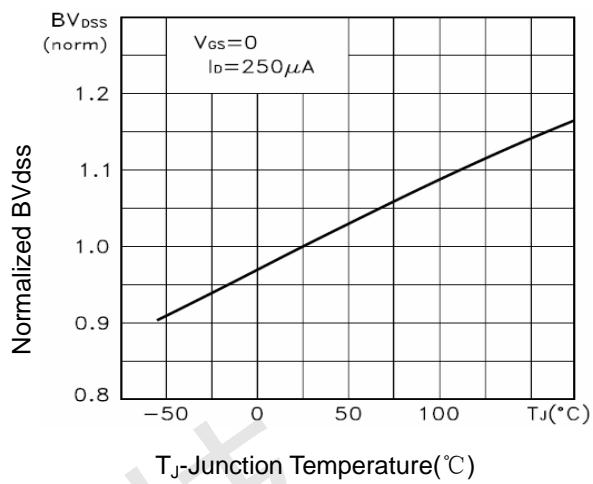


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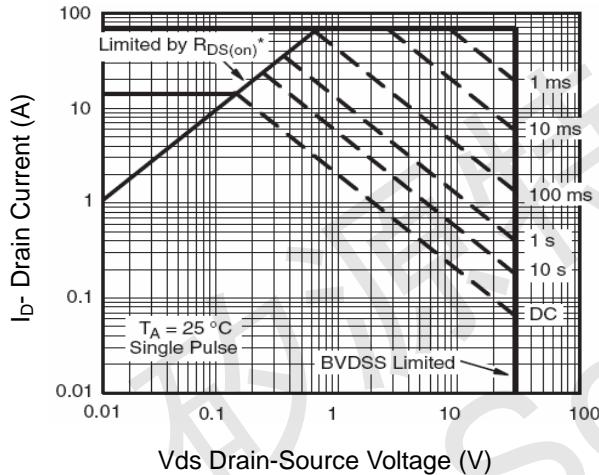
V<sub>ds</sub> Drain-Source Voltage (V)

Figure 7 Capacitance vs Vds



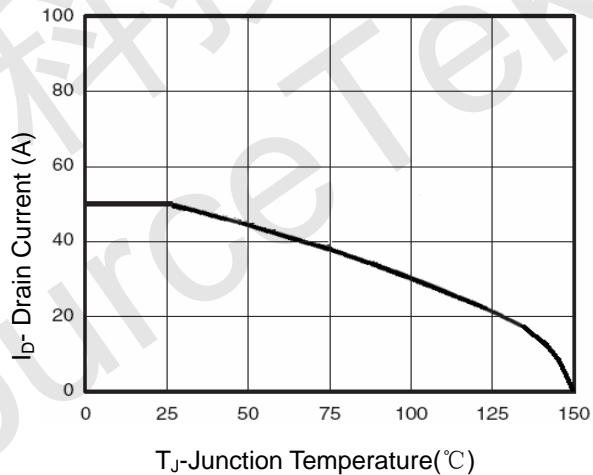
T<sub>J</sub>-Junction Temperature(°C)

Figure 9 BV<sub>dss</sub> vs Junction Temperature



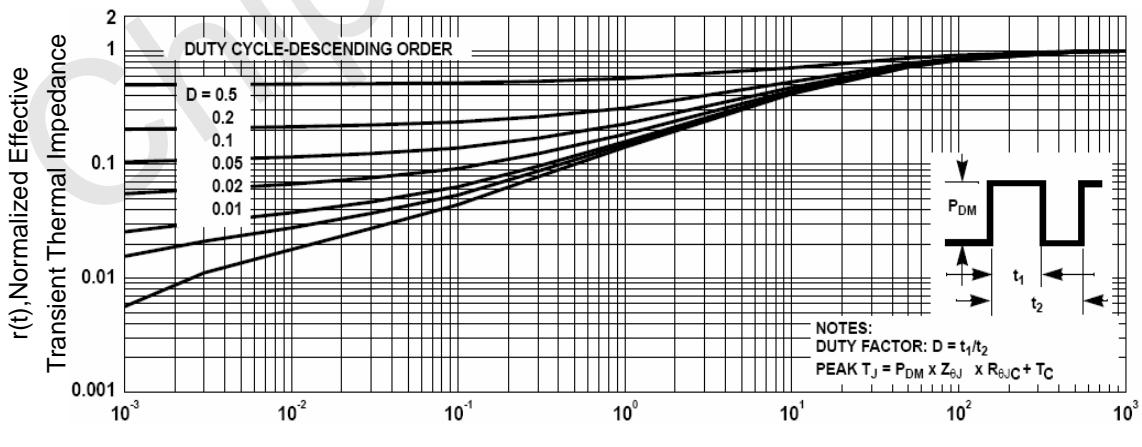
V<sub>ds</sub> Drain-Source Voltage (V)

Figure 8 Safe Operation Area



T<sub>J</sub>-Junction Temperature(°C)

Figure 10 ID Current Derating vs Junction Temperature

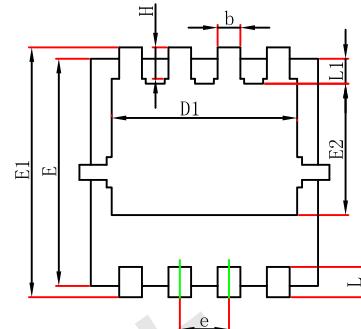
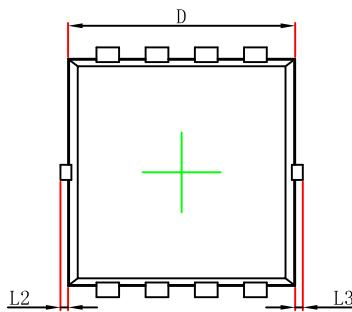
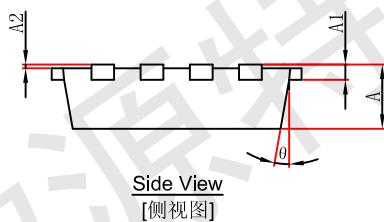


Square Wave Pulse Duration(sec)

Figure 11 Normalized Maximum Transient Thermal Impedance



## PDFNWB(3x3)-8L PACKAGE OUTLINE DIMENSIONS

Top View  
[顶视图]Bottom View  
[背视图]Side View  
[侧视图]

Symbol	Dimensions In Millimeters		Dimensions In Inches	
	Min.	Max.	Min.	Max.
A	0.650	0.850	0.026	0.033
A1	0.152 REF.		0.006 REF.	
A2	0~0.05		0~0.002	
D	2.900	3.100	0.114	0.122
D1	2.300	2.600	0.091	0.102
E	2.900	3.100	0.114	0.122
E1	3.150	3.450	0.124	0.136
E2	1.535	1.935	0.060	0.076
b	0.200	0.400	0.008	0.016
e	0.550	0.750	0.022	0.030
L	0.300	0.500	0.012	0.020
L1	0.180	0.480	0.007	0.019
L2	0~0.100		0~0.004	
L3	0~0.100		0~0.004	
H	0.315	0.515	0.012	0.020
θ	9°	13°	9°	13°